

Search Notes

Application/Control No.

10/612,765

Examiner

John L. Goodrow

Applicant(s)/Patent under
Reexamination

QIAN ET AL.

Art Unit

1756

SEARCHED

Class	Subclass	Date	Examiner
430	117	3/6/2006	JG
	115		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR